

Report No.: EED32L00337602 Page 52 of 71

PHOTOGRAPHS OF TEST SETUP

Test model No.: GD810



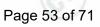
Radiated spurious emission Test SetupTX-1(Below 30MHz)

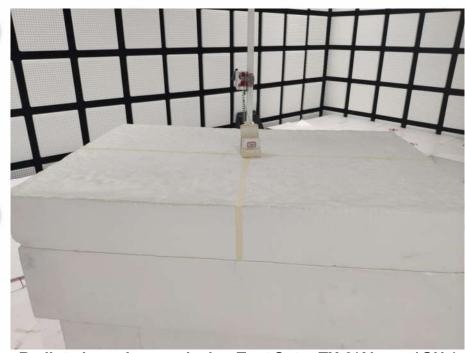


Radiated spurious emission Test SetupTX-2(Below 1GHz)



Report No.: EED32L00337602





Radiated spurious emission Test SetupTX-3(Above 1GHz)



Radiated spurious emission Test SetupRX-4Below 30MHz)







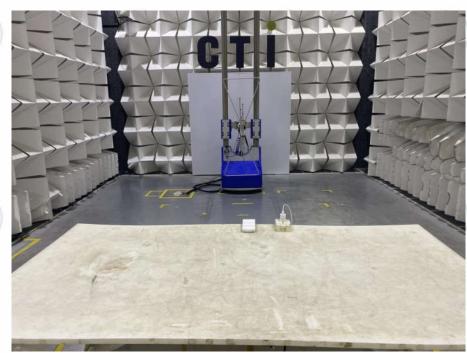






Report No.: EED32L00337602





Radiated spurious emission Test SetupRX-5(Below 1GHz)



Radiated spurious emission Test SetupRX-6Above 1GHz)







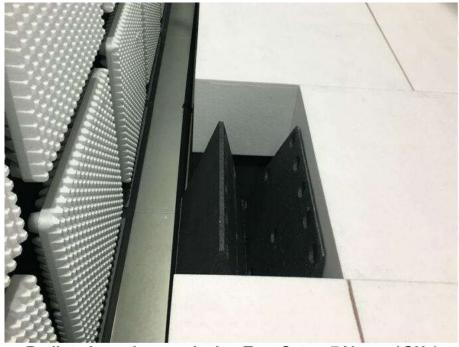






Report No.: EED32L00337602





Radiated spurious emission Test Setup-7Above 1GHz)
There are absorbing materials under the ground.



Conducted Emissions Test Setup-8









